

# Device Reliability Prediction

Case 1 - Black Box Estimates (50% Stress, Temp. = 40 Deg. C, No Device burn-in)

**Date:** 10/4/18

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**Unit:** LMZM23601

**Manufacturer:** Texas Instruments Inc.

<i>Device Type</i>	<i>Qty</i>	<i>Failure Rate</i>	<i>Quality Factor</i>	<i>Total Device Failure Rate</i>
Capacitor, Fixed, Ceramic	2	1	1	2
Inductor, Power Filter	1	19	1	19
IC, Analog	1	0.2	1	0.2
<b><i>Total FIT Rate:</i></b>				21.2
<b><i>Equivalent MTBF (hrs):</i></b>				47,169,811